



Modelithics provides 1/f Noise Characterization Services for on-wafer and packaged transistors and diodes. Measurements are performed in a screen room to minimize local electromagnetic interference and solutions to problems such as biasing filter networks and load resistances are provided.

The system provides a wide frequency response in order to determine corner frequencies for various devices like:

- SiGe HBT
- BJT
- GaAs MESFET
- GaN HEMT
- pHEMT
- HJFET
- Si CMOS

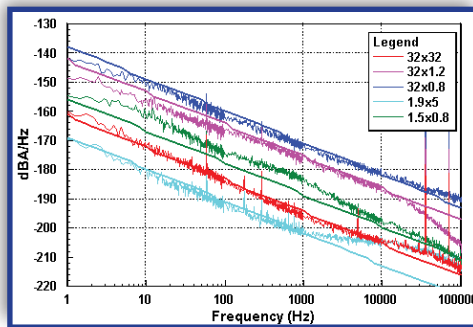
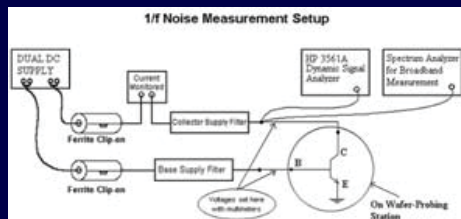
The measurement capability over temperature and over broad frequency ranges enables great versatility in solving your testing requirements. Modelithics can also provide **non-linear transistor and diode models** with 1/f noise fitting to address requirements such as improved phase noise predictions in oscillator designs.

- Standard Noise Testing to 100kHz
- Broad-band Service to 1MHz Also Available.
- On-Wafer Probing Station and Temperature Controller: 25°C to +90°C
- Low Noise Current Pre-Amplifier, Bias Filtering and Battery Supply Operation - As Required.

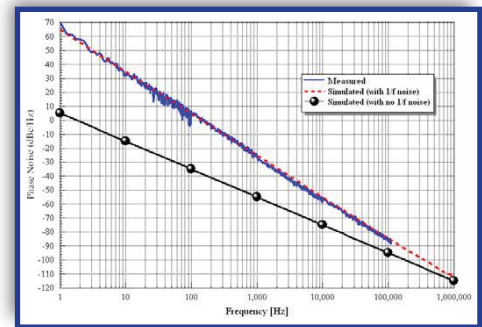
Contact us today to learn more about our noise testing services. Custom hardware and software solutions can be provided to ensure that all your specifications are addressed in the most time- and cost-efficient manner possible.

Sales@Modelithics.com

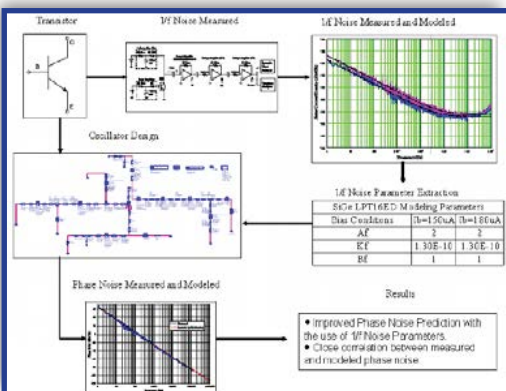
[Visit Our Website to Request a Passive or Active Service Quote](#)



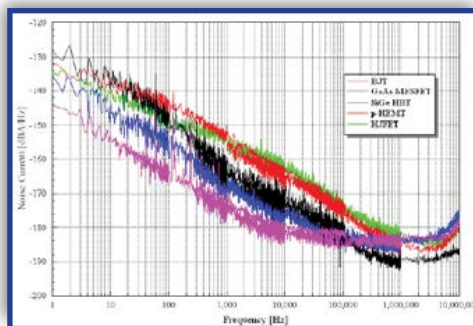
Example: Scalable NMOS BSIM3 Models Versus Measured Data



Improved Phase Noise Prediction with the Use of 1/f Noise Modeling Parameters.



Example: Including 1/f Noise in Simulations



Example: Various Devices Measured Using the Same DC Output Bias

Also Check Out the Other Sides of Modelithics!

- [Modelithics COMPLETE Library - Including 1/f Noise Models](#)
- [Vendor Sponsored Models, Data, and Libraries](#)
- [Modelithics Vendor Partner \(MVP\) Program](#)
- [Test Fixtures and Accessories](#)